

**Search Notes**

Application/Control No.

10/712,159

Examiner

Y. J. Han

Applicant(s)/Patent under  
Reexamination

HOSHINO ET AL.

Art Unit

2838

**SEARCHED**

Class	Subclass	Date	Examiner
323	238		
	246		
	282		
	284		
	285		
	288		
	901		
	908		
363	49	3/05	JH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
323	285		
	288		
	901	3/05	JH

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR